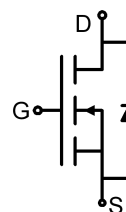


$V_{DSS}$	20V
$R_{DS(on)}$	131mΩ(typ.)
$I_D$	1A



Advanced MOSFET process technology  
 Special designed for PWM, load switching and  
 general purpose applications  
 Ultra low on-resistance with low gate charge  
 Fast switching and reverse body recovery



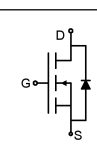
It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

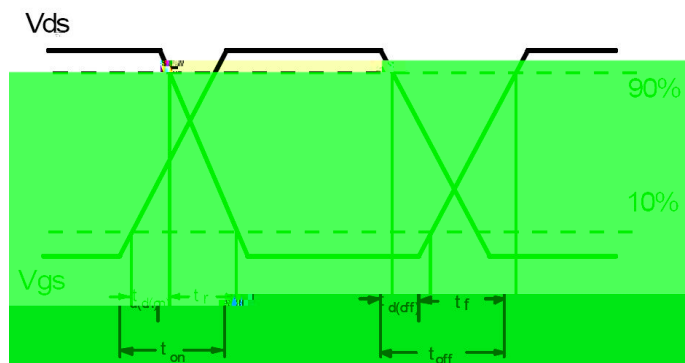
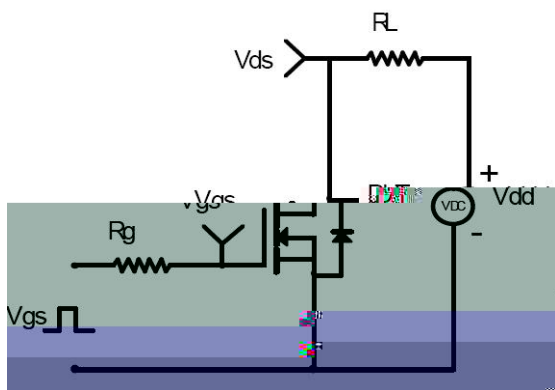
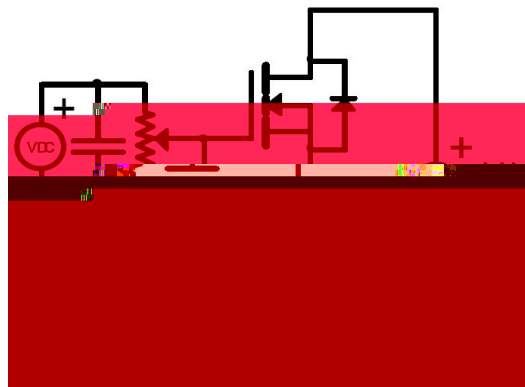
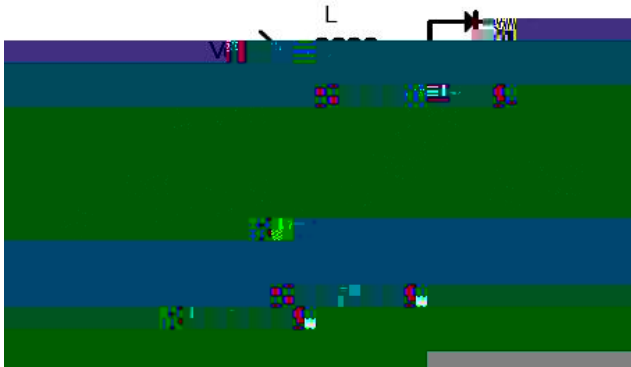
$I_D @ T_A = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	1	A
$I_D @ T_A = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	0.7	
$I_{DM}$	Pulsed Drain Current	4	
$P_D @ T_A = 25^\circ\text{C}$	Power Dissipation	0.23	W
$V_{DS}$	Drain-Source Voltage	20	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 10$	V
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

$R_{\theta JA}$	Junction-to-Ambient	—	543	/W
-----------------	---------------------	---	-----	----

@T<sub>J</sub>=25 unless otherwise specified

$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	20	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	131	170	mΩ	$V_{GS}=4.5V, I_D = 0.5A$
		—	190	247	mΩ	$V_{GS}=2.5V, I_D = 0.3A$
$V_{GS(th)}$	Gate threshold voltage	0.4	—	1	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	μA	$V_{DS} = 20V, V_{GS} = 0V$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	±10	μA	$V_{GS} = \pm 10V, V_{DS} = 0V$
$Q_g$	Total gate charge	—	1.1	—	nC	$I_D = 0.9A,$ $V_{DS} = 10V,$ $V_{GS} = 4.5V$
$Q_{gs}$	Gate-to-Source charge	—	0.27	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	0.21	—		
$t_{d(on)}$	Turn-on delay time	—	2	—	ns	$V_{GS} = 4.5V, V_{DS} = 10V,$ $R_{GEN} = 10\Omega$ $I_D = 0.5A$
$t_r$	Rise time	—	20	—		
$t_{d(off)}$	Turn-Off delay time	—	11	—		
$t_f$	Fall time	—	24	—		
$C_{iss}$	Input capacitance	—	61	—	pF	$V_{GS} = 0V$ $V_{DS} = 10V$ $f = 1MHz$
$C_{oss}$	Output capacitance	—	21	—		
$C_{rss}$	Reverse transfer capacitance	—	13	—		

$I_S$	Continuous Source Current (Body Diode)	—	—	1	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	4	A	
$V_{SD}$	Diode Forward Voltage	—	—	1.2	V	

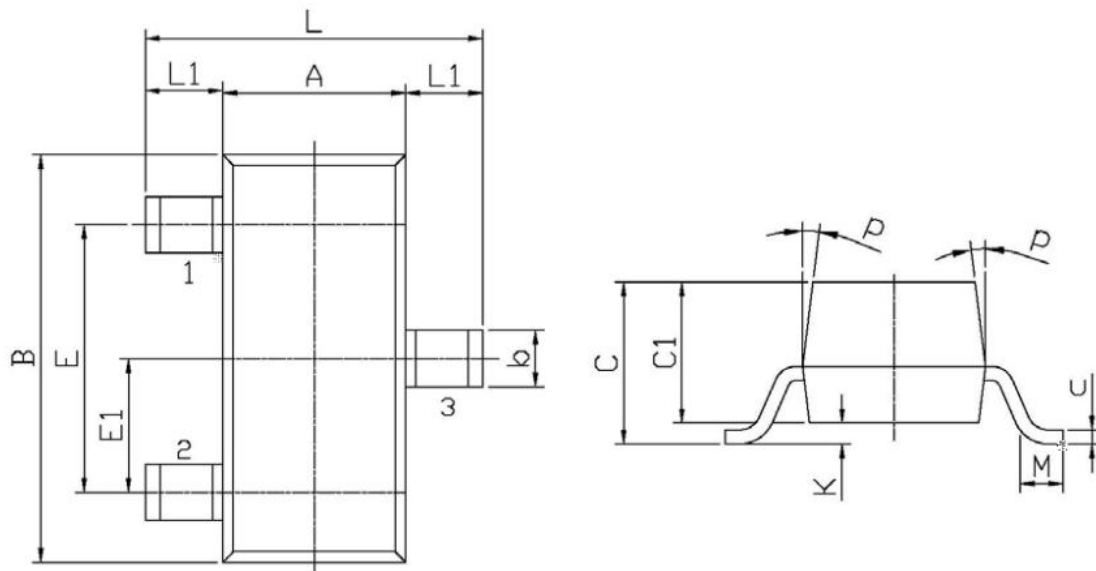


Calculated continuous current based on maximum allowable junction temperature.

Repetitive rating; pulse width limited by max. junction temperature.

The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.

The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25$



Symbol	Dimensions in Millimeter		Symbol	Dimensions in Millimeter	
	Min	Max		Min	Max
L	2.2	2.7	C	1.30 Max	
L1	0.45	0.65	C1	0.90	1.20
A	1.15	1.50	c	0.05	0.20
B	2.70	3.10	K	0	0.10
E	1.70	2.10	M	0.20 Min	
E1	0.85	1.05	P	7°	
b	0.35	0.55			

